

K2159-VB Datasheet

N-Channel 60-V (D-S) MOSFET

PRODUCT SUMMARY							
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^a	Q _g (Typ.)				
60	0.076 at V _{GS} = 10 V	5.5	29 nC				
	0.088 at V _{GS} = 4.5 V	4.5	29110				

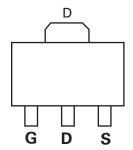
FEATURES

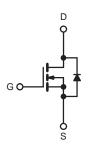
- Halogen-free
- Trench Power MOSFET



APPLICATIONS

Load Switches for Portable Devices





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Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V _{DS}	60	V		
Gate-Source Voltage	V _{GS}	± 20	v		
	T _C = 25 °C		5.5 ^a		
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C	-	4 ^a		
Continuous Diam Current (1) = 130 °C)	T _A = 25 °C	I _D	4.7 ^{a, b, c}		
	T _A = 70 °C		4 ^{a, b, c}	A	
Pulsed Drain Current		I _{DM}	20		
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	5.2		
Continuous Source-Diain Diode Current	T _A = 25 °C	'S	5.1 ^{b, c}		
	T _C = 25 °C		5.3		
Maximum Power Discipation	T _C = 70 °C	P _D	4	W	
Maximum Power Dissipation	T _A = 25 °C	' D	2.5 ^{b, c}	VV	
	T _A = 70 °C		1.6 ^{b, c}		
Operating Junction and Storage Temperatur	T _J , T _{stg}	- 55 to 150	°C		
Soldering Recommendations (Peak Temper	ature) ^{e, f}		260		

THERMAL RESISTANCE RATINGS								
Parameter	Symbol	Typical	Maximum	Unit				
Maximum Junction-to-Ambient ^{a, c, d}	t ≤ 5 s	R _{thJA}	40	50	°C/W			
Maximum Junction-to-Foot (Drain) Steady State		R_{thJF}	15	20]			

- a. Package limited, T_C = 25 °C.
 b. Surface Mounted on 1" x 1" FR4 board.
- d. Maximum under Steady State conditions is 95 °C/W.
- e. See Reliability Manual for profile. The ChipFET is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- f. Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.



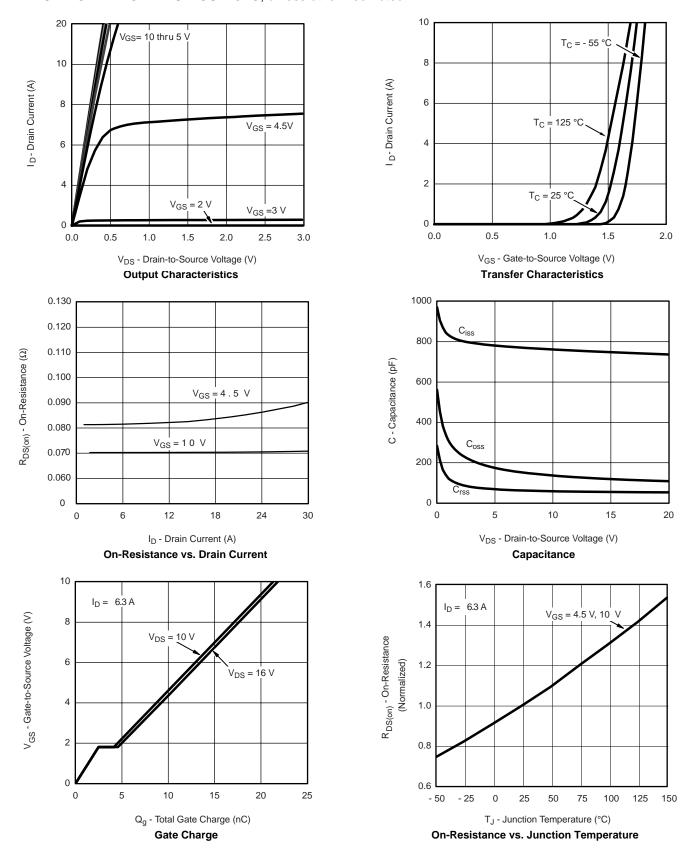
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static	-			1	I.	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$				V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		25		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 4.0		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	1.5		3.0	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 12 \text{ V}$			± 100	nA
Zana Oata Valta na Brain Oanaat		$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}$			1	
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10	μΑ
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 4.5 \text{ V}$	25			Α
		$V_{GS} = 4.5 \text{ V}, I_D = 3.3 \text{ A}$		0.088		Ω
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 10 V, I _D = 4.5 A		0.076		
Forward Transconductance ^a	9 _{fs}	V _{DS} = 10 V, I _D = 4.3 A		45		S
Dynamic ^b		50 . 5				l
Input Capacitance	C _{iss}			800		
Output Capacitance	C _{oss}	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		120		pF
Reverse Transfer Capacitance	C _{rss}			100		
T. 10 . 0		$V_{DS} = 10 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 6.3 \text{ A}$		22	33	nC
Total Gate Charge	Qg			10	15	
Gate-Source Charge	Q _{gs}	$V_{DS} = 10 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 6.3 \text{ A}$		2.5		
Gate-Drain Charge	Q_{gd}			1.7		
Gate Resistance	R _g	f = 1 MHz		2.4		Ω
Turn-on Delay Time	t _{d(on)}			15	25	
Rise Time	t _r	V_{DD} = 10 V, R_L = 1.5 Ω		10	15	
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 6.7$ A, V_{GEN} = 4.5 V, R_g = 1 Ω		35	55	
Fall Time	t _f			12	20	
Turn-on Delay Time	t _{d(on)}			10	15	ns
Rise Time	t _r	V_{DD} = 10 V, R_L = 1.5 Ω		12	20	
Turn-Off Delay Time	t _{d(off)}	$I_D\cong$ 6.7 A, V_{GEN} = 10 V, R_g = 1 Ω		25	40	
Fall Time	t _f			10	15	
Drain-Source Body Diode Characteristi	cs			•		•
Continuous Source-Drain Diode Current	I _S	$T_C = 25 ^{\circ}C$			7.2	^
Pulse Diode Forward Current	I _{SM}				25	A
Body Diode Voltage	V _{SD}	I _S = 6.7 A, V _{GS} = 0 V		0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			20	40	ns
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 6.7 A, dI/dt = 100 A/μs, T _J = 25 °C		10	20	nC
Reverse Recovery Fall Time	t _a	$I_F = 0.7$ A, $U_1/U_1 = 100$ A/ μ s, $I_J = 25$ C		10		
Reverse Recovery Rise Time	t _b			10		ns

Notes:

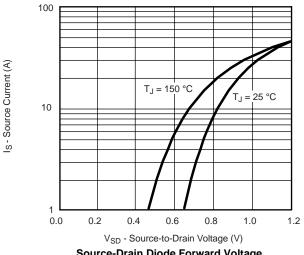
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%$
- b. Guaranteed by design, not subject to production testing.

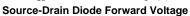
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

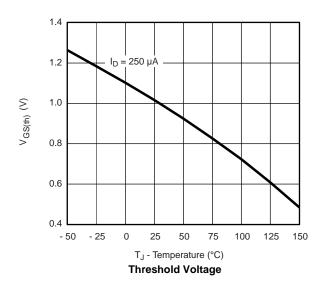


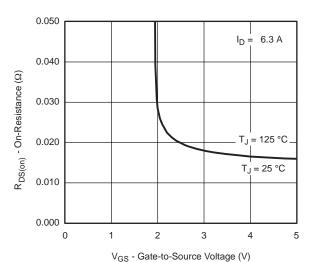




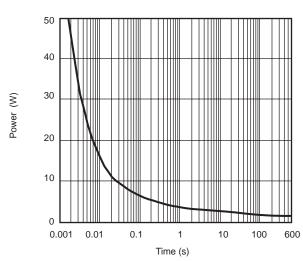




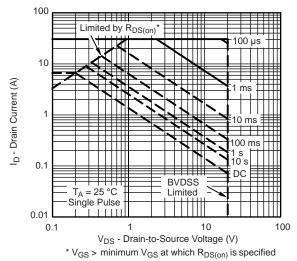




On-Resistance vs. Gate-to-Source Voltage

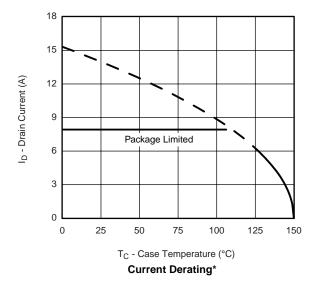


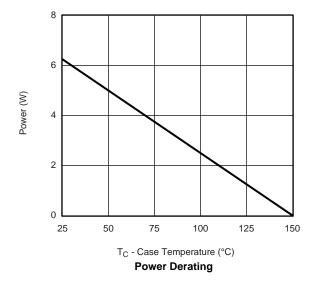
Single Pulse Power



Safe Operating Area, Junction-to-Ambient

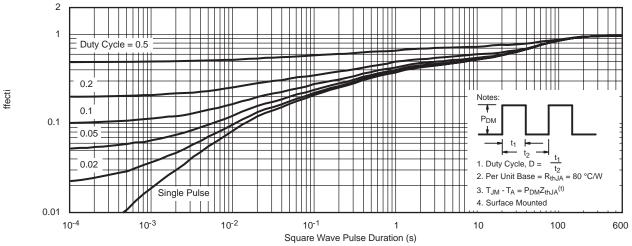




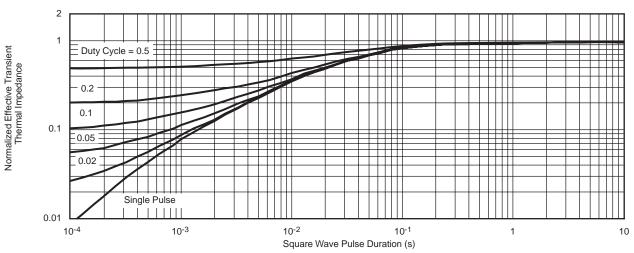


^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





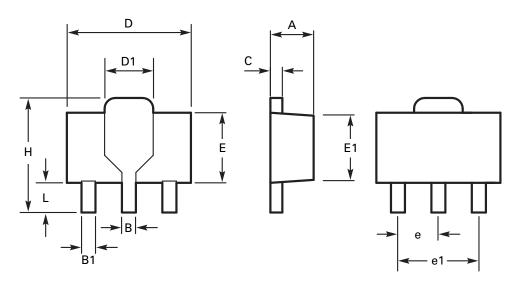
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot



Package outline - SOT89



DIM	Millin	neters	Inc	hes	DIM	Millimeters		Inches	
	Min	Max	Min	Max		Min	Max	Min	Max
Α	1.40	1.60	0.550	0.630	Е	2.29	2.60	0.090	0.102
В	0.44	0.56	0.017	0.022	E1	2.13	2.29	0.084	0.090
B1	0.36	0.48	0.014	0.019	е	1.50 BSC		0.059 BSC	
С	0.35	0.44	0.014	0.017	e1	3.00 BSC		0.118 BSC	
D	4.40	4.60	0.173	0.181	Н	3.94	4.25	0.155	0.167
D1	1.62	1.83	0.064	0.072	L	0.89	1.20	0.035	0.047

Note: Controlling dimensions are in millimeters. Approximate dimensions are provided in inches



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